

**Search Notes**

Application/Control No.

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Examiner

Anish Desai

Applicant(s)/Patent under  
Reexamination

MIYANO ET AL.

Art Unit

1771

**SEARCHED**

Class	Subclass	Date	Examiner

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Inventor search using EAST	9/20/2006	APD
Text search (US-PGPUB, USPAT, USOCR, FPRS, EPO, JPO, DERWENT, IBM_TDB)	9/22/2006	APD
(428/41.6,42.1,354, 343,1.1,542,543), Text search only.	9/22/2006	APD